

Form PTO-1449 (MODIFIED)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 200310116-1		SERIAL NO. Unassigned	
INFORMATION DISCLOSURE CITATION. Date Filed: April 21, 2004 (Use several sheets if necessary)				APPLICANT Xiaofeng YANG et al.			
				FILING DATE 04/21/2004		GROUP ART UNIT 2823 Unassigned	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
QJ	A1	6,615,668 B2	09/09/2003	TOYODA ET AL.			
QJ	A2	6,578,426 B2	08/17/2003	IMAI ET AL.			
QJ	A3	6,211,540 B1	04/03/2001	TAKAHASHI ET AL.			
QJ	A4	5,948,965	09/07/1999	UPCHURCH ET AL.			
QJ	A5	5,595,942	01/21/1997	ALBRECHT			
FOREIGN PATENT DOCUMENTS							
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
QJ	A6	CARL V. THOMPSON et al. "Submicron and Nano Materials: Science and Engineering," Department of Materials Science and Engineering, 13 Sheets.					
QJ	A7	M. HLIWA et al., "Intramolecular Wheatstone Bridge," Intramolecular Wheatstone, September 22, 2003, 2 pages, http://www.cemes.fr/Oper_recherche/nanosciences/9-%20Molecul...					
QJ	A8	D. HOADLEY et al., "Mechanical Strain, Conductance Fluctuations, and Dynamics of Single Tunneling Defects," W. M. Keck Microfabrication Facility, August 5, 2003, 1 page, http://krmf.pa.msu.edu/Research/resrch04.asp .					
QJ	A9	Y. LEE et al., "High-Cycle Fatigue Test of Nanoscale Si and SiO ₂ Wires Based on AFM Technique," Department of Mechanical Engineering, Faculty of Science and Engineering, Ritsumeikan University, 2 pages.					
QJ	A10	M. LUTWYCHE et al., "5X5 2D AFM Cantilever Arrays A First Step Towards A Terabit Storage Device," Sensors and Actuators, 1999, pages 89-94, vol. 73.					
QJ	A11	T. ONDARCUHU et al., "Nanotube Devices," August 5, 2003, 5 pages, http://www.cemes.fr/Oper_recherche/nanosciences/6%20-%20Mole...					
QJ	A12	"Nano Probe", Precision Engineering, September 22, 2003, 2 pages, http://pe.wtb.tue.nl/Personal/bos/probe.htm .					
EXAMINER Shuanda Jia				DATE CONSIDERED 9-7-2005			
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